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Richardson RFPD, Inc.
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26th May 2021

Subject: Additional testing and packaging site.

PCN-1440

Dear Valued Customer,

MACOM Technology Solutions has a goal of providing redundant manufacturing capability for increased surge capacity as well as an uninterrupted supply chain. In alignment with this goal, we are pleased to announce an additional testing and packaging site for the parts listed in the next pages.

In addition to our current testing and packaging sites, we planned to test and package these parts at our long-standing Contract Manufacturer, Year 2000, Ho Chi Minh City, Vietnam. Year 2000 is a valued, high-quality manufacturing partner for many MACOM products.

In accordance with MACOM Technology Solutions' customer notification policy, you are receiving this notice because you have purchased one or more of the products listed in the previous two-year period.

Please contact your local sales representative if you have any specific questions.

Sincerely

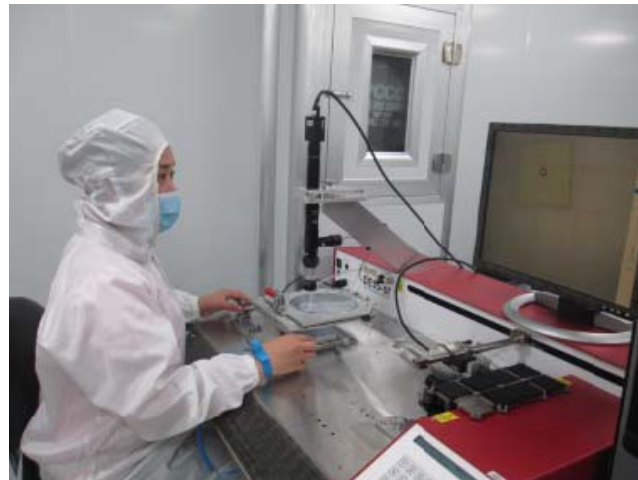
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Appendix I
Affected part numbers

Part Number	Part type
M3X3019	Capacitor
M3X3017	Capacitor
M3X2661	Capacitor
MCC50-50D	Capacitor
M5X5272	Capacitor
MC2S022025-025	Capacitor
910R6J	Capacitor
M3X1833	Capacitor
919R9K	Capacitor
MC2S005010-010	Capacitor
MX51992-11	Capacitor
M3X6183	Capacitor

All the parts to be transferred on this pcn are capacitors. Three representative part numbers(M3X3017, M3X6183 and MCC50D) are tested and qualified in Year 2000(testing data and Cpk see Appendix II), and the rest capacitors can be qualified by similarity to the representative parts.

Appendix II
The new testing and assembly facility

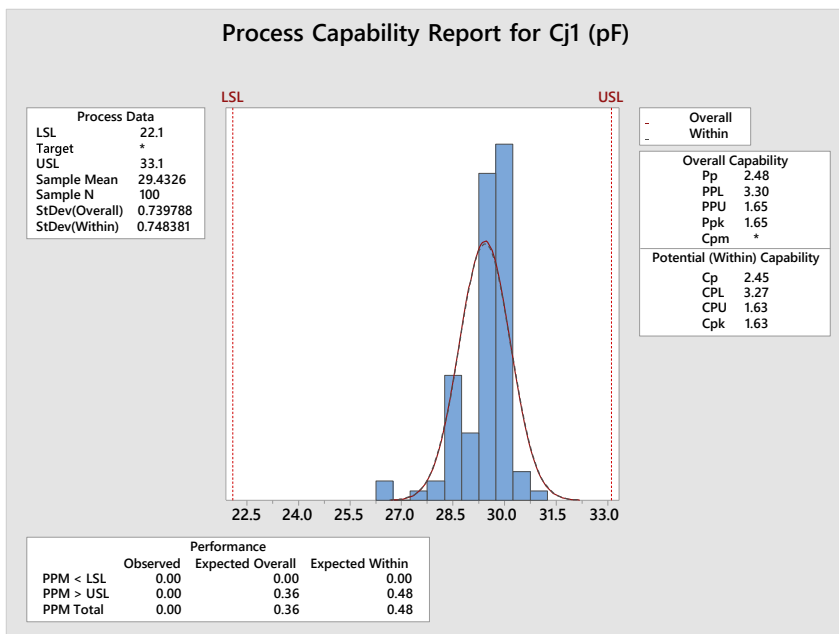
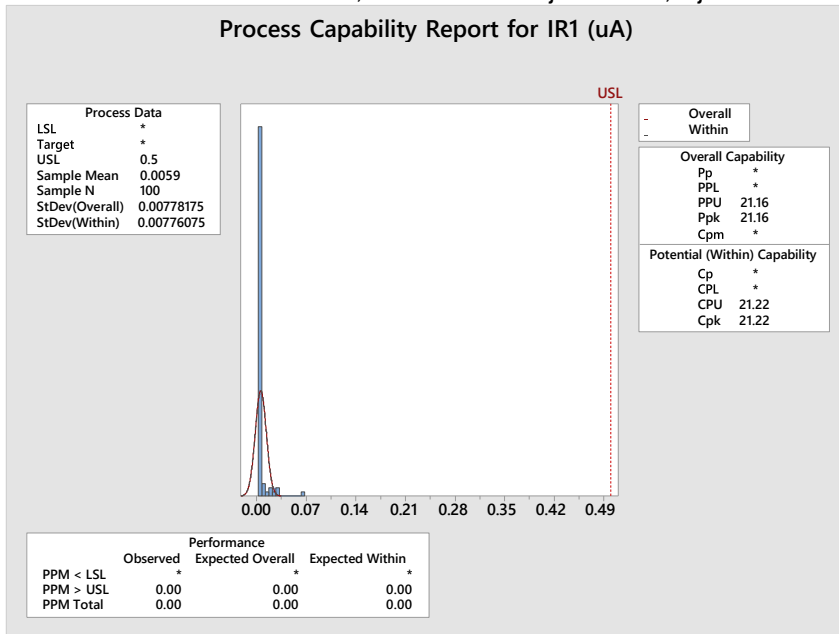


Appendix III

Qualification testing data

1. M3X3017

Test conditions: IRmax=0.5uA, under -100V. Cjmin=22.1, Cjmax=33.1. Sample size=100,10 sub-groups.

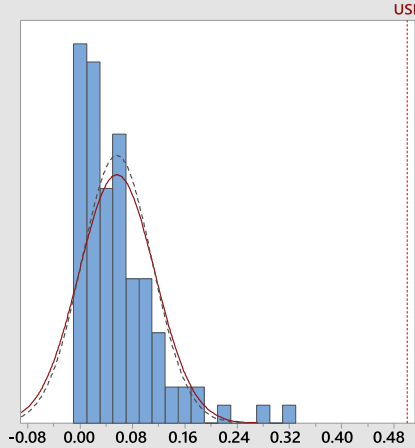


2. M3X6183

Test conditions: IRmax=0.5uA, under -50V. Cjmin=3.76, Cjmax=5.64. Sample size=100,10 sub-groups.

Process Capability Report for IR1 (uA)

Process Data	
LSL	*
Target	*
USL	0.5
Sample Mean	0.05624
Sample N	100
StDev(Overall)	0.0580453
StDev(Within)	0.0538643

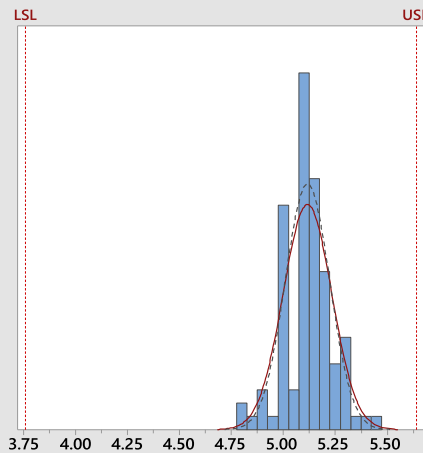


Overall Capability	
Pp	*
PPL	*
PPU	2.55
Ppk	2.55
Cpm	*
Potential (Within) Capability	
Cp	*
CPL	*
CPU	2.75
Cpk	2.75

Performance			
	Observed	Expected Overall	Expected Within
PPM < LSL	*	*	*
PPM > USL	0.00	0.00	0.00
PPM Total	0.00	0.00	0.00

Process Capability Report for Cj1 (pF)

Process Data	
LSL	3.76
Target	*
USL	5.64
Sample Mean	5.1167
Sample N	100
StDev(Overall)	0.117
StDev(Within)	0.107236



Overall Capability	
Pp	2.68
PPL	3.87
PPU	1.49
Ppk	1.49
Cpm	*
Potential (Within) Capability	
Cp	2.92
CPL	4.22
CPU	1.63
Cpk	1.63

Performance			
	Observed	Expected Overall	Expected Within
PPM < LSL	0.00	0.00	0.00
PPM > USL	0.00	3.86	0.53
PPM Total	0.00	3.86	0.53

3. MCC50D

Test conditions: IRmax=0.5uA, under -50V. Cjmin=40, Cjmax=60. Sample size=80,10 sub-groups.

